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Resume of Peter Purdue, Undated

Purdue, Peter

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RESUME OF PETER PURDUE

Peter Purdue was born in Dublin, Ireland on 18 September 1943. He received the Bachelor of Science degree in Mathematic and Chemistry from the University of London (1967) and the Master of Science degree (1969) and Ph.D. degree (1972) in Statistics from Purdue University.

He taught statistics, probability and operations research courses at the University of Kentucky from 1971 to 1984. From 1984 to 1986 he was Program Director for Statistics and Probability at the National Science Foundation, Washington, D. C. In September 1986 he joined the faculty at the Naval Postgraduate School as Professor and Chairman in the Operations Research Department. He has been a Visiting Professor at Virginia Polytechnic Institute and at the University of Umea in Sweden.



His research interests are in Applied Probability and Operations Research.

He is a Fellow of the Institute of Mathematical Statistics, an elected member of the International Statistical Institute and a member of the Operations Research Society of America and the Institute of Management Sciences. He is currently an Associate Editor for Management Sciences and for Applied Stochastic Models and Data Analysis.